1. Record Nr. UNISA996280740303316 IEEE Std 1241-2010 (Revision of IEEE Std 1241-2000): IEEE standard Titolo for terminology and test methods for analog-to-digital converters // **IEEE** [Place of publication not identified]:,: IEEE,, 2011 Pubbl/distr/stampa **ISBN** 0-7381-6239-6 Descrizione fisica 1 online resource Disciplina 621.39814 Soggetti Analog-to-digital converters Electromagnetic waves Lingua di pubblicazione Inglese **Formato** Materiale a stampa Livello bibliografico Monografia The material presented in this standard is intended to provide common Sommario/riassunto terminology and test methods for the testing and evaluation of analogto-digital converters (ADCs). This standard considers only those ADCs whose output values have discrete values at discrete times, i.e., they are quantized and sampled. In general, this quantization is assumed to be nominally uniform (the input-output transfer curve is approximately a straight line) as discussed further in 1.3, Analog-to-digital converter background, and the sampling is assumed to be at a nominally uniform rate. Some but not all of the test methods in this standard can be used for ADCs that are designed for non-uniform quantization. Keywords: ADC, analog-to-digital converter, code transition level, coherent sampling, DNL, ENOB, histogram, INL, LSB, missing codes, noise power ratio, noncoherent sampling, quantization error, quantization noise, SAR, SFDR, sine fitting.